

# WaferWave Technologies | Product Specification

## 100mm Monitor Grade Silicon Wafer (CZ, P-Type, <100>)

### Product Overview:

This high-performance Monitor Grade substrate is sourced from **SEMI-certified European facilities** and is optimized for process monitoring, tool seasoning, and thin-film characterization. Featuring an exceptional Total Thickness Variation (TTV) of <10  $\mu\text{m}$  and ultra-low particle counts, this wafer provides "near-prime" mechanical performance at a cost-effective price point for 2026 manufacturing standards.

### 1. Physical & Crystallographic Properties

Specification	Value
Diameter	100 $\pm$ 0.3 mm
Material	Silicon (Si)
Growth Method	Czochralski (CZ)
Grade	Test / Monitor Grade
Type / Dopant	P-Type / Boron (P/B)
Crystal Orientation	<100> $\pm$ 0.5°
Resistivity	> 1 $\Omega\cdot\text{cm}$

## 2. Mechanical Specifications

Specification	Value
Thickness	525 ± 25 µm
Total Thickness Variation (TTV)	< 10 µm
Bow	< 30 µm
Warp	< 30 µm
Orientation Features	2 SEMI-Standard Flats

## 3. Surface & Purity Control

Specification	Value
Surface Finish (Front)	Mirror Polished (SSP)
Surface Finish (Back)	Etched / Standard Finish
Particle Count	< 10 ea/wf (@ ≥ 0.5 µm)

## 4. Packaging & Documentation

Specification	Value
Packaging	25-Slot Polypropylene Cassette (Standard Wafer Jar)

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**Origin**

European Union (Germany)

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**Compliance**Full Certificate of Analysis (COA) /  
Conformance (COC) included

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